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1 An embedded autonomous scan-based results analyzer (EARA) for SoC cores

Nahvi, M.; Ivanov, A.;

VLSI Test Symposium, 2003. Proceedings. 21st , 27 April-1 May 2003

Pages:293 - 298

[\[Abstract\]](#) [\[PDF Full-Text \(3467 KB\)\]](#) **IEEE CNF**

2 Non-intrusive built-in self-test for FPGA and MCM applications

Russ, A.D.; Stroud, C.E.;

AUTOTESTCON '95. 'Systems Readiness: Test Technology for the 21st Century'. Conference Record , 8-10 Aug. 1995

Pages:480 - 485

[\[Abstract\]](#) [\[PDF Full-Text \(608 KB\)\]](#) **IEEE CNF**